

REMARKS

In view of the above amendments and following remarks, Applicants request favorable reconsideration of the above-identified application.


Claims 29 and 32-38 are now pending in this application, with Claims 29, 32, 35 and 36 being independent. By this Amendment, Applicants have amended Claims 29 and 32, and added new Claims 35-38. No new matter has been added.

Applicants would like to thank the Examiner for extending the courtesy of granting an interview to Applicants' representative on November 1, 2005. During that interview, Applicants' representative explained to the Examiner that none of the cited references (U.S. Patent Nos. 5,772,905 (Chou); 3,894,710 (Sarofeen); and 6,157,488 (Ishii)) describes or suggests the use of recess and protrusion alignment marks to provide engagement between a mold and a substrate on which a first diffraction grating is formed. While those documents variously discuss the use of recess and protrusion alignment marks, even in combination they fail to suggest the use of such marks in the engagement of a mold and a substrate on which a first diffraction grating is formed, in connection with molding a second diffraction grating in alignment with the first diffraction grating.

To clarify such features of the invention, Applicants have amended the previous independent claims and added new independent claims. Applicants respectfully request that the Examiner consider the amendments and new claims when the application is next taken up for action, and withdraw the outstanding rejections in view of the same.

Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should continue to be directed to our below-listed address.

Respectfully submitted,



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